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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

| | |
|----------------------------|---|
| Product Status | Discontinued at Digi-Key |
| Core Processor | XC800 |
| Core Size | 8-Bit |
| Speed | 24MHz |
| Connectivity | I ² C, SSC, UART/USART |
| Peripherals | Brown-out Detect/Reset, LED, POR, PWM, WDT |
| Number of I/O | 23 |
| Program Memory Size | 8KB (8K x 8) |
| Program Memory Type | FLASH |
| EEPROM Size | - |
| RAM Size | 512 x 8 |
| Voltage - Supply (Vcc/Vdd) | 2.5V ~ 5.5V |
| Data Converters | A/D 8x10b |
| Oscillator Type | Internal |
| Operating Temperature | -40°C ~ 85°C (TA) |
| Mounting Type | Surface Mount |
| Package / Case | 28-TSSOP (0.173", 4.40mm Width) |
| Supplier Device Package | PG-TSSOP-28-1 |
| Purchase URL | https://www.e-xfl.com/product-detail/infineon-technologies/xc836t2friabfxuma1 |

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Summary of Features

Features: (continued)

- Power saving modes
 - idle mode
 - power-down mode with wake-up capability via real-time clock event
 - clock gating control to each peripheral
- Programmable 16-bit Watchdog Timer (WDT) running on independent oscillator with programmable window feature for refresh operation and warning prior to overflow
- Three general purpose I/O ports
 - 4 high current I/O
 - 2 high sink I/O
 - Up to 25 pins as digital I/O
 - Up to 8 pins as digital/analog input
- Up to 8 channels, 10-bit A/D Converter
 - support up to 7 differential input channel
 - results filtering by data reduction or digital low-pass filter, for up to 13-bit results
- Up to 8 channels, Out of range comparator
- Three 16-bit timers
 - Timer 0 and Timer 1 (T0 and T1)
 - Timer 2 (T2)
- Real-time clock with 32.768 kHz crystal pad
- 16-bit Vector Computer for Field-Oriented Control (FOC)
 - Multiplication/Division Unit (MDU) for arithmetic calculation
 - CORDIC Unit for trigonometric calculation
- Capture and Compare unit for PWM signal generation (CCU6)
- A full-duplex or half-duplex serial interface (UART)
- Synchronous serial channel (SSC)
- Inter-IC (IIC) serial interface
- LED and Touch-sense Controller (LEDTSCU)
- Software libraries to support fixed-point control and EEPROM emulation
- On-chip debug support via single pin DAP interface (SPD)
- Packages:
 - PG-DSO-24
 - PG-TSSOP-28
- Temperature range T_A :
 - SAF (-40 to 85 °C)
 - SAK (-40 to 125 °C)

Summary of Features

Ordering Information

The ordering code for Infineon Technologies microcontrollers provides an exact reference to the required product. This ordering code identifies:

- The derivative itself, i.e. its function set, the temperature range, and the supply voltage
- The package and the type of delivery

For the available ordering codes for the XC835/836, please refer to your responsible sales representative or your local distributor.

2 General Device Information

Chapter 2 contains the block diagram, pin configurations, definitions and functions of the XC835/836.

2.1 Block Diagram

The block diagram of the XC835/836 is shown in Figure 2.

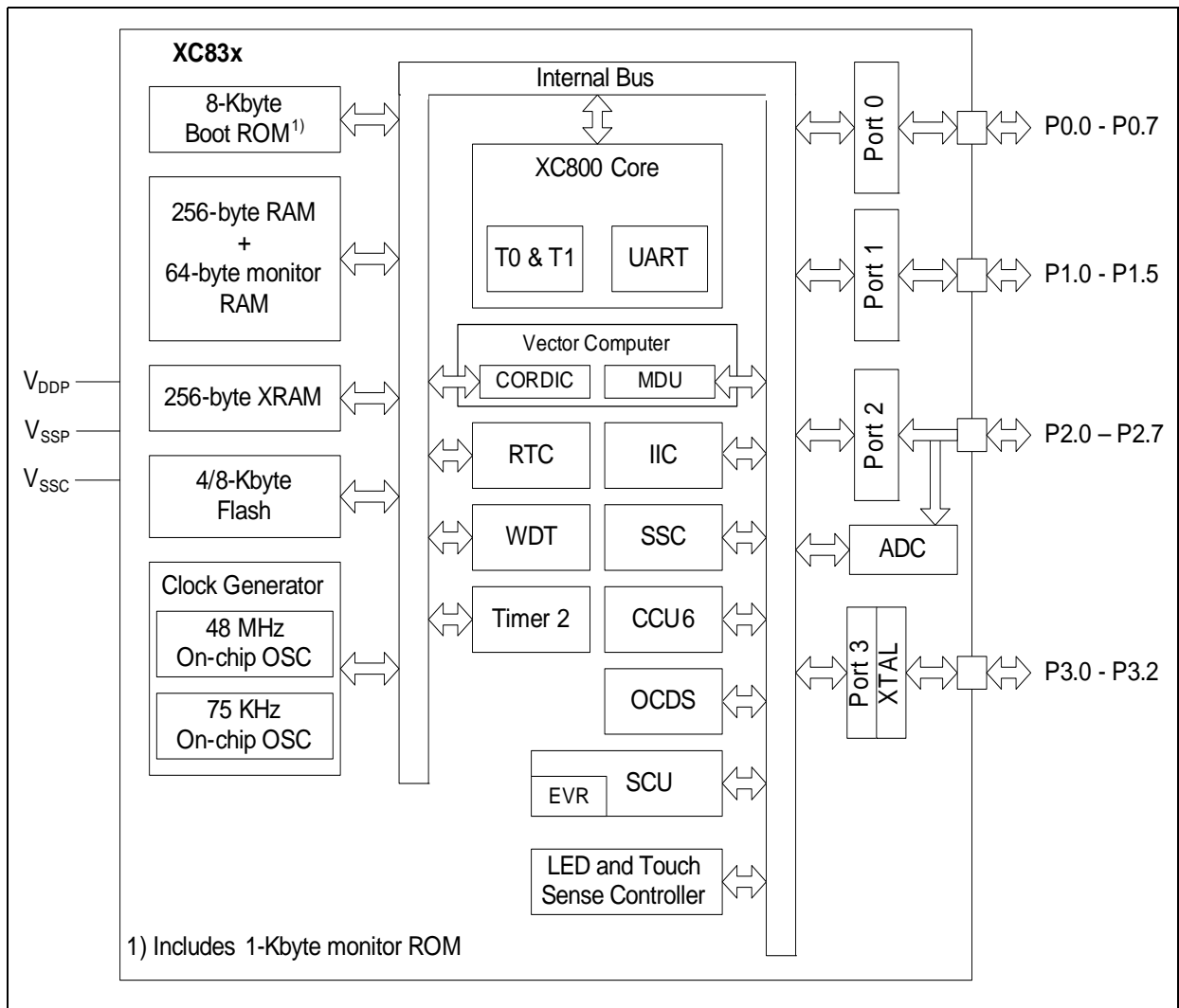


Figure 2 XC835/836 Block Diagram

2.2 Logic Symbol

The logic symbol of the XC835/836 is shown in [Figure 3](#).

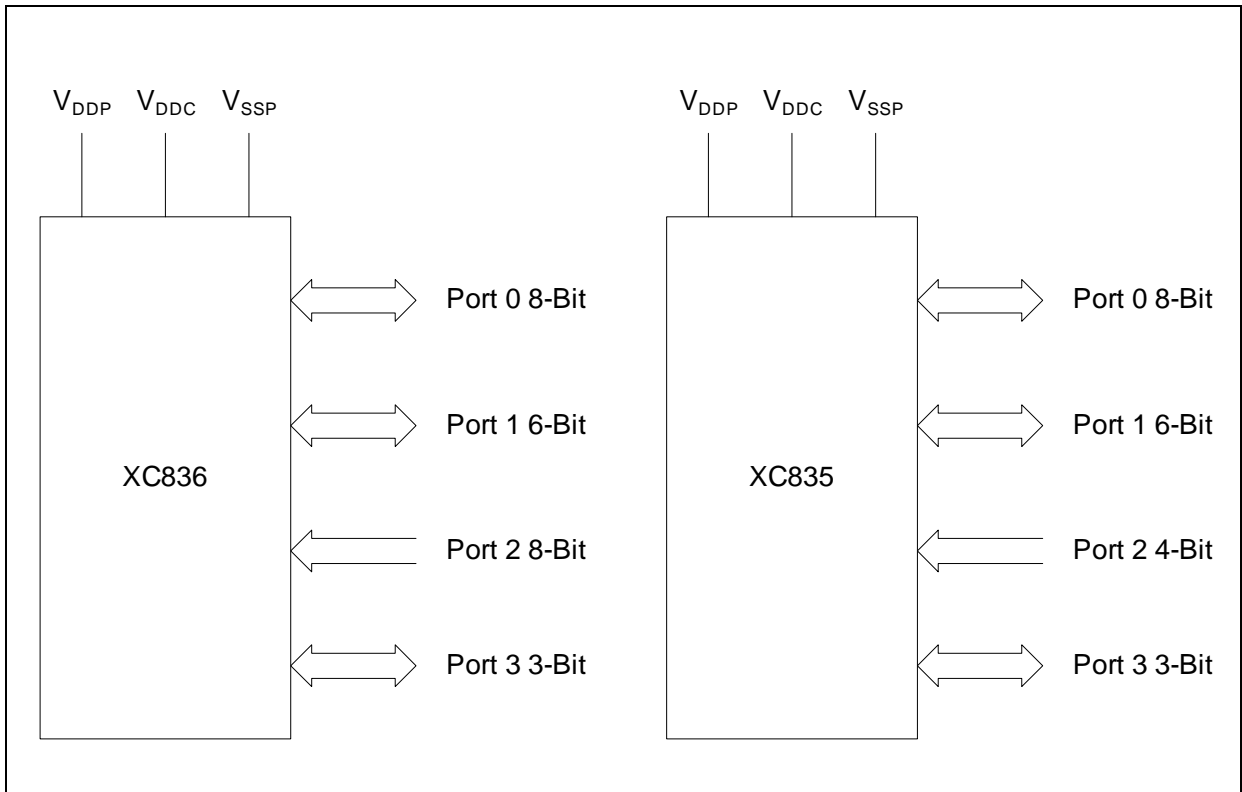


Figure 3 XC835/836 Logic Symbol

General Device Information
Table 3 Pin Definitions and Functions for XC835/836 (cont'd)

| Symbol | Pin Number TSSOP28/ DS024 | Type | Reset State | Function |
|--------|---------------------------------|------|-------------|--|
| P1.0 | 16/14 | | Hi-Z | SPD_2 SPD Input/Output RXD_2 UART Receive Input T2EX_2 Timer 2 External Trigger Input EXINT0_2 External Interrupt Input 0 COL0_0 LED Column 0 COUT60_0 Output of Capture/Compare Channel 0 TXD_1 UART Transmit Output |
| P1.1 | 15/13 | | Hi-Z | CC60_0 Input/Output of Capture/Compare channel 0 COL1_0 LED Column 1 TXD_2 UART Transmit Output |
| P1.2 | 14/12 | | Hi-Z | EXINT4 External Interrupt Input 4 COL2_0 LED Column 2 COUT61_0 Output of Capture/Compare channel 1 COUT63_1 Output of Capture/Compare channel 3 |
| P1.3 | 13/11 | | Hi-Z | CC61_0 Input/Output of Capture/Compare channel 1 COL3_0 LED Column 3 EXF2_2 Timer 2 Overflow Flag |
| P1.4 | 19/17 | | Hi-Z | EXINT5 External Interrupt Input 5 COL4 LED Column 4 COUT62_0 Output of Capture/Compare channel 2 COUT63_2 Output of Capture/Compare channel 3 |

General Device Information
Table 3 Pin Definitions and Functions for XC835/836 (cont'd)

| Symbol | Pin Number TSSOP28/ DS024 | Type | Reset State | Function |
|-----------|---------------------------------|----------|-------------|---|
| P1.5 | 20/18 | | Hi-Z | CC62_0 Input/Output of Capture/Compare channel 2 COL5 LED Column 5 COLA_1 LED Column A |
| P2 | | I | | Port 2 Port 2 is a general purpose input-only port. It can be used as inputs for A/D Converter and out of range comparator, CCU6, Timer 2, SSC and UART. |
| P2.0 | 8/6 | | Hi-Z | CCPOS0_1 CCU6 Hall Input 0 T12HR_2 CCU6 Timer 12 Hardware Run Input T13HR_2 CCU6 Timer 13 Hardware Run Input T2EX_3 Timer 2 External Trigger Input T2_1 Timer 2 Input EXINT0_3 External Interrupt Input 0 AN0 Analog Input 0 / Out of range comparator channel 0 |
| P2.1 | 7/5 | | Hi-Z | CCPOS1_1 CCU6 Hall Input 1 RXD_5 UART Receive Input MTRSR_6 SSC Slave Receive Input T0_1 Timer 0 Input EXINT1_1 External Interrupt Input 1 AN1 Analog Input 1 / Out of range comparator channel 1 |

General Device Information
Table 3 Pin Definitions and Functions for XC835/836 (cont'd)

| Symbol | Pin Number TSSOP28/ DS024 | Type | Reset State | Function |
|--------|---------------------------------|------|-------------|---|
| P2.2 | 6/4 | | Hi-Z | CCPOS2_1 CCU6 Hall Input 2 T12HR_3 CCU6 Timer 12 Hardware Run Input T13HR_3 CCU6 Timer 13 Hardware Run Input SCK_3 SSC Clock Input/Output T1_1 Timer 1 Input EXINT2_0 External Interrupt Input 2 AN2 Analog Input 2 / Out of range comparator channel 2 |
| P2.3 | 5/3 | | Hi-Z | CCPOS0_2 CCU6 Hall Input 0 CTRAP_2 CCU6 Trap Input T2_2 Timer 2 Input EXINT3 External Interrupt Input 3 AN3 Analog Input 3 / Out of range comparator channel 3 |
| P2.4 | 4/- | | Hi-Z | T12HR_5 CCU6 Timer 12 Hardware Run Input T13HR_5 CCU6 Timer 13 Hardware Run Input T2_3 Timer 2 Input AN4 Analog Input 4 / Out of range comparator channel 4 |
| P2.5 | 3/- | | Hi-Z | T12HR_7 CCU6 Timer 12 Hardware Run Input T13HR_7 CCU6 Timer 13 Hardware Run Input AN5 Analog Input 5 / Out of range comparator channel 5 |

General Device Information

Table 3 Pin Definitions and Functions for XC835/836 (cont'd)

| Symbol | Pin Number TSSOP28/ DS024 | Type | Reset State | Function |
|-----------|---------------------------------|------|-------------|---|
| P2.6 | 2/- | | Hi-Z | SCK_2 SSC Clock Input/Output EXINT6 External Interrupt Input 6 AN6 Analog Input 6 / Out of range comparator channel 6 |
| P2.7 | 1/- | | Hi-Z | RXD_6 UART Receive Input T2EX_6 Timer 2 External Trigger Input MTRSR_7 SSC Slave Receive Input EXINT0_4 External Interrupt Input 0 AN7 Analog Input 7 / Out of range comparator channel 7 |
| P3 | | I/O | | Port 3 Port 3 is a bidirectional general purpose I/O port. It can be used as alternate functions for IIC, LEDTSCU, UART, Timer 2, SSC, SPD and 32.768 kHz crystal pad. |
| P3.0 | 26/24 | | PU | SCL_2 IIC Clock Line SCK_1 SSC Clock Input/Output EXINT2_1 External Interrupt Input 2 COL6 LED Column 6 XTAL4 32.768 kHz External Oscillator Output |

3 Electrical Parameters

Chapter 3 provides the characteristics of the electrical parameters which are implementation-specific for the XC835/836.

3.1 General Parameters

The general parameters are described here to aid the users in interpreting the parameters mainly in **Section 3.2** and **Section 3.3**.

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XC835/836 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

- **CC**
 - These parameters indicate **C**ontroller **C**haracteristics, which are distinctive features of the XC835/836 and must be regarded for a system design.
- **SR**
 - These parameters indicate **S**ystem **R**equirements, which must be provided by the microcontroller system in which the XC835/836 is designed in.

3.1.2 Absolute Maximum Rating

Maximum ratings are the extreme limits to which the XC835/836 can be subjected to without permanent damage.

Table 6 Absolute Maximum Rating Parameters

| Parameter | Symbol | Limit Values | | Unit | Notes |
|--|------------------|--------------|------|------|------------|
| | | Min. | Max. | | |
| Ambient temperature | T_A | -40 | 125 | °C | under bias |
| Storage temperature | T_{ST} | -65 | 150 | °C | – |
| Junction temperature | T_J | -40 | 150 | °C | under bias |
| Voltage on power supply pin with respect to V_{SS} | V_{DDP} | -0.5 | 6 | V | |
| Maximum current per pin for P1[3:0] | I_M | -115 | 115 | mA | |
| Input current on any pin during overload condition | I_{IN} | -10 | 10 | mA | |
| Absolute sum of all input currents during overload condition | $\Sigma I_{IN} $ | – | 50 | mA | |

Note: Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. During absolute maximum rating overload conditions ($V_{IN} > V_{DDP}$ or $V_{IN} < V_{SS}$) the voltage on V_{DDP} pin with respect to ground (V_{SS}) must not exceed the values defined by the absolute maximum ratings.

3.2 DC Parameters

The electrical characteristics of the DC Parameters are detailed in this section.

3.2.1 Input/Output Characteristics

Table 8 provides the characteristics of the input/output pins of the XC835/836.

Table 8 Input/Output Characteristics (Operating Conditions apply)

| Parameter | Symbol | Limit Values | Unit | Test Conditions | |
|--|---------------|------------------|------|-----------------|--|
| | | | | | Min. |
| Output low voltage on port pins (all except P1) | V_{OLP} CC | – | 1.0 | V | $I_{OL} = 25 \text{ mA (5 V)}$ $I_{OL} = 13 \text{ mA (3.3 V)}$ |
| | | – | 0.4 | V | $I_{OL} = 10 \text{ mA (5 V)}$ $I_{OL} = 5 \text{ mA (3.3 V)}$ |
| Output low voltage on P1[3:0] | V_{OLP1} CC | – | 1.0 | V | $I_{OL} = 50 \text{ mA (5 V)}$ $I_{OL} = 25 \text{ mA (3.3 V)}$ |
| | | – | 0.32 | V | $I_{OL} = 20 \text{ mA (5 V)}$ |
| | | – | 0.4 | V | $I_{OL} = 10 \text{ mA (3.3 V)}$ |
| Output low voltage on P1[5:4] | V_{OLP2} CC | – | 1.0 | V | $I_{OL} = 50 \text{ mA (5 V)}$ $I_{OL} = 25 \text{ mA (3.3 V)}$ |
| | | – | 0.4 | V | $I_{OL} = 20 \text{ mA (5 V)}$ $I_{OL} = 10 \text{ mA (3.3 V)}$ |
| Output high voltage on port pins (all except P1) | V_{OHP} CC | $V_{DDP} - 1.0$ | – | V | $I_{OH} = -15 \text{ mA (5 V)}$ $I_{OH} = -8 \text{ mA (3.3 V)}$ |
| | | $V_{DDP} - 0.4$ | – | V | $I_{OH} = -5 \text{ mA (5 V)}$ $I_{OH} = -2.5 \text{ mA (3.3 V)}$ |
| Output high voltage on P1[3:0] | V_{OHP1} CC | $V_{DDP} - 0.32$ | – | V | $I_{OH} = -20 \text{ mA (5 V)}$ |
| | | $V_{DDP} - 1.0$ | – | V | $I_{OH} = -25 \text{ mA (3.3 V)}$ |
| | | $V_{DDP} - 0.4$ | – | V | $I_{OH} = -10 \text{ mA (3.3 V)}$ |
| Output high voltage on P1[5:4] | V_{OHP2} CC | $V_{DDP} - 1.0$ | – | V | $I_{OH} = -30 \text{ mA (5 V)}$ $I_{OH} = -16 \text{ mA (3.3 V)}$ |
| | | $V_{DDP} - 0.4$ | – | V | $I_{OH} = -10 \text{ mA (5 V)}$ $I_{OH} = -5 \text{ mA (3.3 V)}$ |

Electrical Parameters
Table 8 Input/Output Characteristics (Operating Conditions apply) (cont'd)

| Parameter | Symbol | | Limit Values | | Unit | Test Conditions |
|---|-------------|----|--------------|------|------|-----------------|
| | | | Min. | Max. | | |
| Voltage on any pin during V_{DDP} power off | V_{PO} | SR | – | 0.3 | V | 5) |
| Maximum current per pin (excluding P1, V_{DDP} and V_{SS}) | I_{MP} | SR | -15 | 25 | mA | – |
| Maximum current per pin for P1[3:0] | I_{MP1A} | SR | -50 | 50 | mA | – |
| Maximum current per pin for P1[5:4] | I_{MP1B} | SR | -30 | 50 | mA | – |
| Maximum current into V_{DDP} | I_{MVDDP} | SR | – | 130 | mA | 4) |
| Maximum current out of V_{SS} | I_{MVSS} | SR | – | 130 | mA | 4) |

- 1) Not subjected to production test, verified by design/characterization. Hysteresis is implemented to avoid meta stable states and switching due to internal ground bounce. It cannot be guaranteed that it suppresses switching due to external system noise.
- 2) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin.
- 3) Over current detection is available for 5V application only.
- 4) Not subjected to production test, verified by design/characterization.
- 5) Not subjected to production test, verified by design/characterization. However, for applications with strict low power-down current requirements, it is mandatory that no active voltage source is supplied at any GPIO pin when V_{DDP} is powered off.

3.2.2 Supply Threshold Characteristics

Table 9 provides the characteristics of the supply threshold in the XC835/836.

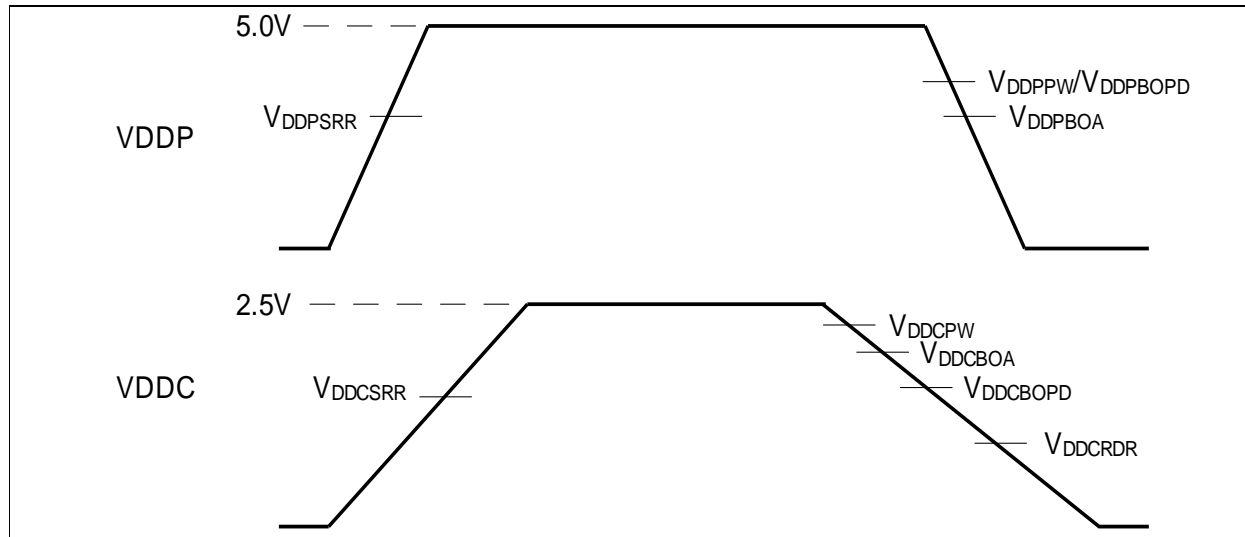


Figure 8 Supply Threshold Parameters

Table 9 Supply Threshold Parameters (Operating Conditions apply)

| Parameters | Symbol | | Limit Values | | | Unit |
|---|---------------|----|--------------|------|------|------|
| | | | Min. | Typ. | Max. | |
| V_{DDP} prewarning voltage ¹⁾²⁾ | V_{DDPPW} | CC | 3.0 | 3.6 | 4.5 | V |
| V_{DDP} brownout voltage in active mode ²⁾³⁾ | V_{DDPBOA} | CC | 2.65 | 2.75 | 2.87 | V |
| V_{DDP} brownout voltage in all power down mode ²⁾³⁾ | $V_{DDPBOPD}$ | | 3.0 | 3.6 | 4.5 | V |
| V_{DDP} system reset release voltage ²⁾⁴⁾ | V_{DDPSRR} | CC | 2.7 | 2.8 | 2.92 | V |
| V_{DDC} prewarning voltage ²⁾⁵⁾ | V_{DDCPW} | CC | 2.3 | 2.4 | 2.48 | V |
| V_{DDC} brownout voltage in active mode ²⁾ | V_{DDCBOA} | CC | 2.25 | 2.3 | 2.42 | V |
| V_{DDC} brownout voltage in power down mode ²⁾ | $V_{DDCBOPD}$ | CC | 1.35 | 1.5 | 1.95 | V |
| V_{DDC} system reset release voltage ²⁾⁴⁾ | V_{DDCSRR} | CC | 2.28 | 2.3 | 2.47 | V |
| RAM data retention voltage | V_{DDCRDR} | CC | 1.1 | – | – | V |

1) Detection is enabled via SDCON register in active mode. It is automatically disabled in power down mode. Detection should be disabled for V_{DDP} less than maximum of V_{DDPPW} .

2) This parameter has a hysteresis of 50 mV.

3) Detection is enabled via SDCON register. Detection must be disabled for application with V_{DDP} less than the specified values.

4) V_{DDPSRR} and V_{DDCSRR} must be met before the system reset is released.

5) Detection is enabled via SDCON register in active mode. It is automatically disabled in power down mode.

3.2.3 ADC Characteristics

The values in **Table 10** are given for an analog power supply of 5.0 V. The ADC can be used with an analog power supply down to 3 V. But in this case, analog parameters may show a reduced performance. In the reduced voltage mode ($2.5\text{ V} < V_{DDP} < 3\text{ V}$), the ADC is not recommended to be used.

Table 10 ADC Characteristics (Operating Conditions apply; $V_{DDP} = 5\text{ V}$; $f_{ADCI} \leq 12\text{ MHz}$)

| Parameter | Symbol | | Limit Values | | | Unit | Test Conditions / Remarks |
|--|---------------|----|-------------------------------------|-----------|------------|---------------|---|
| | | | Min. | Typ. | Max. | | |
| Analog reference voltage | V_{AREF} | | – | V_{DDP} | – | V | Connect internally to V_{DDP} |
| Analog reference ground | V_{AGND} | | – | V_{SSP} | – | V | Connect internally to V_{SSP} |
| Alternate analog reference ground | $V_{AGNDALT}$ | SR | $V_{SSP} - 0.1$ | – | $2.5^{1)}$ | V | Connect to AN0 in differential mode, See Figure 9 . |
| Internal voltage reference | V_{INTREF} | SR | 1.19 | 1.23 | 1.28 | V | ⁴⁾ |
| Analog input voltage range | V_{AIN} | SR | V_{AGND} | – | V_{AREF} | V | – |
| ADC clock | f_{ADCI} | | 8 | – | 16 | MHz | internal analog clock |
| Sample time | t_S | CC | $(2 + INPCR0.STC) \times t_{ADCI}$ | | | μs | – |
| Conversion time | t_C | CC | See Section 3.2.3.1 | | | μs | – |
| Set-up time between conversions using internal voltage reference | t_{SETUP} | SR | – | 35 | – | μs | ²⁾ |

Electrical Parameters
Table 10 ADC Characteristics (Operating Conditions apply; $V_{DDP} = 5\text{ V}$; $f_{ADCI} \leq 12\text{ MHz}$) (cont'd)

| Parameter | Symbol | | Limit Values | | | Unit | Test Conditions / Remarks |
|---|-------------|----|--------------|------|-----------|------------|---|
| | | | Min. | Typ. | Max. | | |
| Total unadjusted error | $TUE^{3)}$ | CC | – | – | ± 1 | LSB8 | 8-bit conversion with internal reference ⁴⁾ |
| | | | – | – | +4/-2 | LSB10 | 10-bit conversion with internal reference ⁴⁾⁵⁾ |
| | | | – | – | +14/-2 | LSB12 | 12-bit conversion using the Low Pass Filter ⁴⁾ |
| Differential Nonlinearity | EA_{DNL} | CC | – | – | +1.5/ -1 | LSB | 10-bit conversion ⁴⁾ |
| Integral Nonlinearity | EA_{INL} | CC | – | – | ± 1.5 | LSB | 10-bit conversion ⁴⁾ |
| Offset | EA_{OFF} | CC | – | +4 | – | LSB | 10-bit conversion ⁴⁾ |
| Gain | EA_{GAIN} | CC | – | -4 | – | LSB | 10-bit conversion ⁴⁾ |
| Switched capacitance at an analog input | C_{AINSW} | CC | – | 2 | 3 | pF | ⁴⁾⁶⁾ |
| Total capacitance at an analog input | C_{AINT} | CC | – | – | 12 | pF | ⁴⁾⁶⁾ |
| Input resistance of an analog input | R_{AIN} | CC | – | 1.5 | 2 | k Ω | ⁴⁾ |

1) 1.2 V at $V_{DDP} = 3.0\text{ V}$.

2) Not subject to production test, verified at CPU clock ($f_{SCLK, CCLK}$) = 8 MHz, $T_A = +25\text{ }^\circ\text{C}$ and $V_{DDP} = 5\text{ V}$.

3) TUE is tested at $V_{AREF} = V_{DDP} = 5.0\text{ V}$ and CPU clock ($f_{SCLK, CCLK}$) = 8 MHz.

4) Not subject to production test, verified by design/characterization.

5) If a reduced positive reference voltage is used, TUE will increase. If the positive reference is reduced by a factor of K, the TUE will increased by 1/K. Example:K = 0.8, 1/K = 1.25; 1.25 X TUE = 2.5 LSB10.

6) The sampling capacity of the conversion C-Network is pre-charged to $V_{AREF}/2$ before connecting the input to the C-Network. Because of the parasitic elements, the voltage measured at ANx is lower than $V_{AREF}/2$.

3.2.4 Flash Memory Parameters

The XC835/836 is delivered with all Flash sectors erased (read all zeros).

The data retention time of the XC835/836's Flash memory (i.e. the time after which stored data can still be retrieved) depends on the number of times the Flash memory has been erased and programmed.

Note: Flash memory parameters are not subject to production test but verified by design and/or characterization.

Table 12 Flash Timing Parameters (Operating Conditions apply)

| Parameter | Symbol | CC | Limit Values | | | Unit | Remarks |
|----------------------------------|---------------|----|--------------|------|------|------|--------------------|
| | | | Min. | Typ. | Max. | | |
| Read access time (per byte) | t_{ACC} | CC | – | 125 | – | ns | |
| Programming time (per wordline) | t_{PR} | CC | – | 2.2 | – | ms | |
| Erase time (one or more sectors) | t_{ER} | CC | – | 120 | – | ms | |
| Flash wait states | $N_{WSFLASH}$ | CC | 0 | | | | CPU clock = 8 MHz |
| | | | 1 | | | | CPU clock = 24 MHz |

Table 13 Flash Data Retention and Endurance (Operating Conditions apply)

| Retention | Endurance ¹⁾ | Size | Remarks |
|-----------|-------------------------|----------------|---------|
| 20 years | 1,000 cycles | up to 8 Kbytes | |
| 5 years | 10,000 cycles | 1 Kbyte | |
| 2 years | 70,000 cycles | 512 bytes | |
| 2 years | 100,000 cycles | 128 bytes | |

1) One cycle refers to the programming of all wordlines in a sector and erasing of sector. The Flash endurance data specified in **Table 13** is valid only if the following conditions are fulfilled:

- the maximum number of erase cycles per Flash sector must not exceed 100,000 cycles.
- the maximum number of erase cycles per Flash bank must not exceed 300,000 cycles.
- the maximum number of program cycles per Flash bank must not exceed 2,500,000 cycles.

Table 14 Emulated Flash Data Retention and Endurance based on EEPROM Emulation ROM Library (Operating Conditions apply)

| Retention | Endurance ¹⁾ | Emulation Size | Remarks |
|-----------|-------------------------|----------------|---------|
| 2 years | 1,600,000 cycles | 31 bytes | |
| 2 years | 1,400,000 cycles | 62 bytes | |
| 2 years | 1,200,000 cycles | 93 bytes | |
| 2 years | 1,000,000 cycles | 124 bytes | |

1) These values show the maximum endurance. Maximum endurance is the maximum possible unique data write if each data update is only 31 bytes. Minimum endurance cycle is the maximum possible unique data write if each data update is the same as the emulation size. The minimum endurance cycle can be calculated using the formulae [(max. endurance)*(31)/(emulation size)].

3.3.5 SSC Timing

3.3.5.1 SSC Master Mode Timing

Table 22 provides the SSC master mode timing in the XC835/836.

Table 22 SSC Master Mode Timing¹⁾ (Operating Conditions apply; CL = 50 pF)

| Parameter | Symbol | | Limit Values | | Unit |
|----------------------|--------|----|--------------------|------|------|
| | | | Min. | Max. | |
| SCLK clock period | t_0 | CC | $2 * T_{SSC}^{2)}$ | – | ns |
| MTSR delay from SCLK | t_1 | CC | 0 | 3 | ns |
| MRST set-up to SCLK | t_2 | SR | 32 | – | ns |
| MRST hold from SCLK | t_3 | SR | 0 | – | ns |

1) Not subject to production test, verified by design/characterisation.

2) $T_{SSCmin} = T_{CPU} = 1/f_{CPU}$. When $f_{CPU} = 24$ MHz, $t_0 = 83.3$ ns. T_{CPU} is the CPU clock period.

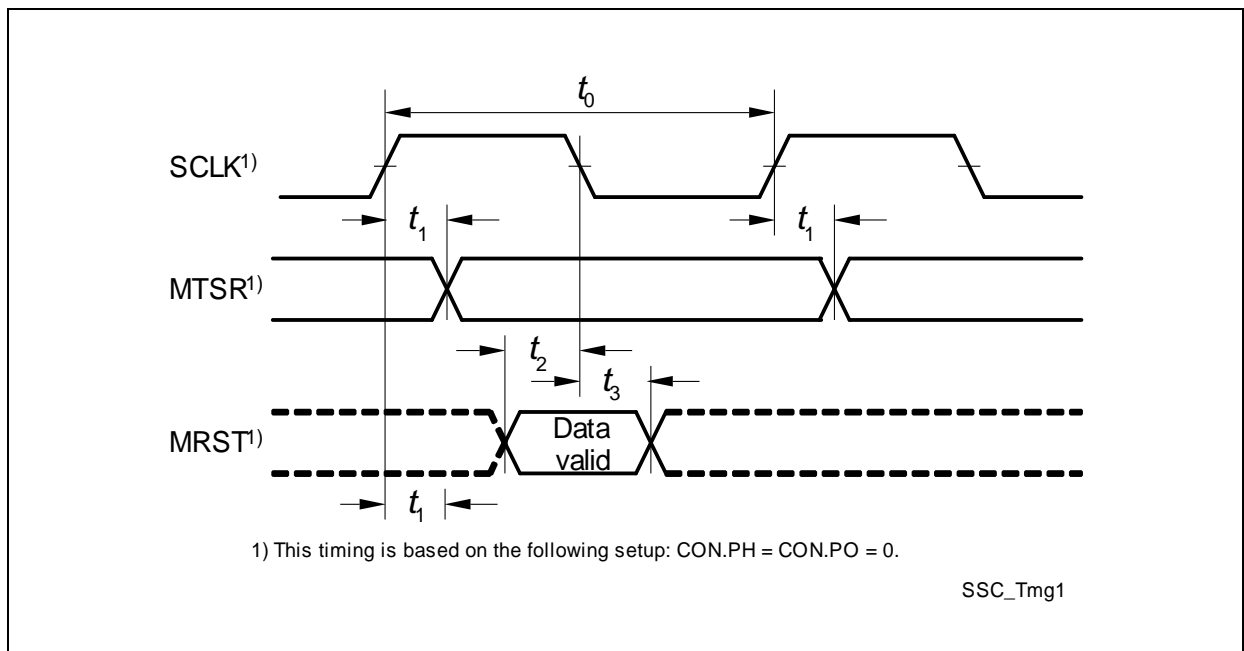


Figure 15 SSC Master Mode Timing

Package and Quality Declaration
4.3 Quality Declaration

Table 25 shows the characteristics of the quality parameters in the XC835/836.

Table 25 Quality Parameters

| Parameter | Symbol | Limit Values | | Unit | Notes |
|--|-----------|--------------|--------|-------|---|
| | | Min. | Max. | | |
| Operation Lifetime when the device is used at the three stated T_J ¹⁾ | t_{OP1} | - | 1500 | hours | $T_J = 150^\circ\text{C}$ |
| | | - | 15000 | hours | $T_J = 110^\circ\text{C}$ |
| | | - | 1500 | hours | $T_J = -40^\circ\text{C}$ |
| Operation Lifetime when the device is used at the stated T_J ¹⁾ | t_{OP2} | - | 131400 | hours | $T_J = 27^\circ\text{C}$ |
| ESD susceptibility according to Human Body Model (HBM) | V_{HBM} | - | 2000 | V | Conforming to EIA/JESD22-A114-B ²⁾ |
| ESD susceptibility according to Charged Device Model (CDM) pins | V_{CDM} | - | 500 | V | Conforming to JESD22-C101-C ²⁾ |

1) This lifetime refers only to the time when device is powered-on.

2) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.